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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

# Details

E·XFI

Product Status	Active
Core Processor	8051
Core Size	8-Bit
Speed	50MHz
Connectivity	EBI/EMI, I <sup>2</sup> C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, POR, PWM, WDT
Number of I/O	62
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3245axi-166t

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Table 2-2 shows the pinout for the 72-pin CSP package. Since there are four  $V_{DDIO}$  pins, the set of I/O pins associated with any  $V_{DDIO}$  may sink up to 100 mA total, same as for the 100-pin and 68-pin devices.

<b>T</b>	~ ~	000	D1
lable	2-2.	CSP	Pinout

Ball	Name	Ball	Name	Ball	Name
G6	P2[5]	F1	VDDD	A5	VDDA
E5	P2[6]	E1	VSSD	A6	VSSD
F5	P2[7]	E2	VCCD	B6	P12[2]
J7	P12[4]	C1	P15[0]	C6	P12[3]
H6	P12[5]	C2	P15[1]	A7	P0[0]
J6	VSSB	D2	P3[0]	B7	P0[1]
J5	Ind	D3	P3[1]	B5	P0[2]
H5	VBOOST	D4	P3[2]	C5	P0[3]
J4	VBAT	D5	P3[3]	A8	VIO0
H4	VSSD	B4	P3[4]	D6	P0[4]
J3	XRES_N	B3	P3[5]	D7	P0[5]
H3	P1[0]	A1	VIO3	C7	P0[6]
G3	P1[1]	B2	P3[6]	C8	P0[7]
H2	P1[2]	A2	P3[7]	E8	VCCD
J2	P1[3]	C3	P12[0]	F8	VSSD
G4	P1[4]	C4	P12[1]	G8	VDDD
G5	P1[5]	E3	P15[2]	E7	P15[4]
J1	VIO1	E4	P15[3]	F7	P15[5]
F4	P1[6]	B1 <sup>[10]</sup>	NC	G7	P2[0]
F3	P1[7]	B8 <sup>[10]</sup>	NC	H7	P2[1]
H1	P12[6]	D1 <sup>[10]</sup>	NC	H8	P2[2]
G1	P12[7]	D8 <sup>[10]</sup>	NC	F6	P2[3]
G2	P15[6]	A3	VCCA	E6	P2[4]
F2	P15[7]	A4	VSSA	J8	VIO2

Figure 2-7 and Figure 2-8 show an example schematic and an example PCB layout, for the 100-pin TQFP part, for optimal analog performance on a two layer board.

- The two pins labeled VDDD must be connected together.
- The two pins labeled VCCD must be connected together, with capacitance added, as shown in Figure 2-7 and Power System on page 31. The trace between the two VCCD pins should be as short as possible.
- The two pins labeled VSSD must be connected together.

For information on circuit board layout issues for mixed signals, refer to the application note AN57821 - Mixed Signal Circuit Board Layout Considerations for PSoC® 3 and PSoC 5.





# Figure 2-8. Example PCB Layout for 100-pin TQFP Part for Optimal Analog Performance

# 3. Pin Descriptions

# IDAC0

Low resistance output pin for high current DAC (IDAC).

# Extref0, Extref1

External reference input to the analog system.

# GPIO

General purpose I/O pin provides interfaces to the CPU, digital peripherals, analog peripherals, interrupts, LCD segment drive, and CapSense.

# 12C0: SCL, 12C1: SCL

 $I^2C$  SCL line providing wake from sleep on an address match. Any I/O pin can be used for  $I^2C$  SCL if wake from sleep is not required.

# 12C0: SDA, 12C1: SDA

 $\rm I^2C$  SDA line providing wake from sleep on an address match. Any I/O pin can be used for  $\rm I^2C$  SDA if wake from sleep is not required.

# Ind

Inductor connection to boost pump.

# kHz XTAL: Xo, kHz XTAL: Xi

32.768-kHz crystal oscillator pin.

# MHz XTAL: Xo, MHz XTAL: Xi

4- to 25- MHz crystal oscillator pin.

# nTRST

Optional JTAG test reset programming and debug port connection to reset the JTAG connection.

# SIO

Special I/O provides interfaces to the CPU, digital peripherals and interrupts with a programmable high threshold voltage, analog comparator, high sink current, and high impedance state when the device is unpowered.

# SWDCK

Serial wire debug clock programming and debug port connection.

# SWDIO

Serial wire debug input and output programming and debug port connection.

# SWV.

Single wire viewer debug output.

# тск

JTAG test clock programming and debug port connection.

# TDI

JTAG test data in programming and debug port connection.

# TDO

JTAG test data out programming and debug port connection.

# TMS

JTAG test mode select programming and debug port connection.





# 4.4.2 DMA Features

- 24 DMA channels
- Each channel has one or more transaction descriptors (TDs) to configure channel behavior. Up to 128 total TDs can be defined
- TDs can be dynamically updated
- Eight levels of priority per channel
- Any digitally routable signal, the CPU, or another DMA channel, can trigger a transaction
- Each channel can generate up to two interrupts per transfer
- Transactions can be stalled or canceled
- Supports transaction size of infinite or 1 to 64k bytes
- TDs may be nested and/or chained for complex transactions

#### 4.4.3 Priority Levels

The CPU always has higher priority than the DMA controller when their accesses require the same bus resources. Due to the system architecture, the CPU can never starve the DMA. DMA channels of higher priority (lower priority number) may interrupt current DMA transfers. In the case of an interrupt, the current transfer is allowed to complete its current transaction. To ensure latency limits when multiple DMA accesses are requested simultaneously, a fairness algorithm guarantees an interleaved minimum percentage of bus bandwidth for priority levels 2 through 7. Priority levels 0 and 1 do not take part in the fairness algorithm and may use 100 percent of the bus bandwidth. If a tie occurs on two DMA requests of the same priority level, a simple round robin method is used to evenly share the allocated bandwidth. The round robin allocation can be disabled for each DMA channel, allowing it to always be at the head of the line. Priority levels 2 to 7 are guaranteed the minimum bus bandwidth shown in Table 4-7 after the CPU and DMA priority levels 0 and 1 have satisfied their requirements.



#### 4.4.4.2 Auto Repeat DMA

Auto repeat DMA is typically used when a static pattern is repetitively read from system memory and written to a peripheral. This is done with a single TD that chains to itself.

#### 4.4.4.3 Ping Pong DMA

A ping pong DMA case uses double buffering to allow one buffer to be filled by one client while another client is consuming the

#### Table 4-7. Priority Levels

Priority Level	% Bus Bandwidth
0	100.0
1	100.0
2	50.0
3	25.0
4	12.5
5	6.2
6	3.1
7	1.5

When the fairness algorithm is disabled, DMA access is granted based solely on the priority level; no bus bandwidth guarantees are made.

#### 4.4.4 Transaction Modes Supported

The flexible configuration of each DMA channel and the ability to chain multiple channels allow the creation of both simple and complex use cases. General use cases include, but are not limited to:

#### 4.4.4.1 Simple DMA

In a simple DMA case, a single TD transfers data between a source and sink (peripherals or memory location). The basic timing diagrams of DMA read and write cycles are shown in Figure 4-1. For more description on other transfer modes, refer to the Technical Reference Manual.

# Figure 4-1. DMA Timing Diagram



data previously received in the other buffer. In its simplest form, this is done by chaining two TDs together so that each TD calls the opposite TD when complete.

#### 4.4.4.4 Circular DMA

Circular DMA is similar to ping pong DMA except it contains more than two buffers. In this case there are multiple TDs; after the last TD is complete it chains back to the first TD.



# 4.4.4.5 Scatter Gather DMA

In the case of scatter gather DMA, there are multiple noncontiguous sources or destinations that are required to effectively carry out an overall DMA transaction. For example, a packet may need to be transmitted off of the device and the packet elements, including the header, payload, and trailer, exist in various noncontiguous locations in memory. Scatter gather DMA allows the segments to be concatenated together by using multiple TDs in a chain. The chain gathers the data from the multiple locations. A similar concept applies for the reception of data onto the device. Certain parts of the received data may need to be scattered to various locations in memory for software processing convenience. Each TD in the chain specifies the location for each discrete element in the chain.

#### 4.4.4.6 Packet Queuing DMA

Packet queuing DMA is similar to scatter gather DMA but specifically refers to packet protocols. With these protocols, there may be separate configuration, data, and status phases associated with sending or receiving a packet.

For instance, to transmit a packet, a memory mapped configuration register can be written inside a peripheral, specifying the overall length of the ensuing data phase. The CPU can set up this configuration information anywhere in system memory and copy it with a simple TD to the peripheral. After the configuration phase, a data phase TD (or a series of data phase TDs) can begin (potentially using scatter gather). When the data phase TD(s) finish, a status phase TD can be invoked that reads some memory mapped status information from the peripheral and copies it to a location in system memory specified by the CPU for later inspection. Multiple sets of configuration, data, and status phase "subchains" can be strung together to create larger chains that transmit multiple packets in this way. A similar concept exists in the opposite direction to receive the packets.

#### 4.4.4.7 Nested DMA

One TD may modify another TD, as the TD configuration space is memory mapped similar to any other peripheral. For example, a first TD loads a second TD's configuration and then calls the second TD. The second TD moves data as required by the application. When complete, the second TD calls the first TD, which again updates the second TD's configuration. This process repeats as often as necessary.

# 4.5 Interrupt Controller

The interrupt controller provides a mechanism for hardware resources to change program execution to a new address, independent of the current task being executed by the main code. The interrupt controller provides enhanced features not found on original 8051 interrupt controllers:

- Thirty two interrupt vectors
- Jumps directly to ISR anywhere in code space with dynamic vector addresses
- Multiple sources for each vector
- Flexible interrupt to vector matching
- Each interrupt vector is independently enabled or disabled
- Each interrupt can be dynamically assigned one of eight priorities
- Eight level nestable interrupts
- Multiple I/O interrupt vectors
- Software can send interrupts
- Software can clear pending interrupts

When an interrupt is pending, the current instruction is completed and the program counter is pushed onto the stack. Code execution then jumps to the program address provided by the vector. After the ISR is completed, a RETI instruction is executed and returns execution to the instruction following the previously interrupted instruction. To do this the RETI instruction pops the program counter from the stack.

If the same priority level is assigned to two or more interrupts, the interrupt with the lower vector number is executed first. Each interrupt vector may choose from three interrupt sources: Fixed Function, DMA, and UDB. The fixed function interrupts are direct connections to the most common interrupt sources and provide the lowest resource cost connection. The DMA interrupt sources provide direct connections to the two DMA interrupt sources provided per DMA channel. The third interrupt source for vectors is from the UDB digital routing array. This allows any digital signal available to the UDB array to be used as an interrupt source. Fixed function interrupts and all interrupt sources may be routed to any interrupt vector using the UDB interrupt source connections.

Figure 4-2 on page 21 represents typical flow of events when an interrupt triggered. Figure 4-3 on page 22 shows the interrupt structure and priority polling.



# Table 6-1. Oscillator Summary

Source	Fmin	Tolerance at Fmin	Fmax	Tolerance at Fmax	Startup Time
IMO	3 MHz	±2% over voltage and temperature	24 MHz	±4%	13-µs max
MHzECO	4 MHz	Crystal dependent	25 MHz	Crystal dependent	5 ms typ, max is crystal dependent
DSI	0 MHz	Input dependent	33 MHz	Input dependent	Input dependent
PLL	24 MHz	Input dependent	50 MHz	Input dependent	250 µs max
Doubler	48 MHz	Input dependent	48 MHz	Input dependent	1 µs max
ILO	1 kHz	-50%, +100%	100 kHz	-55%, +100%	15 ms max in lowest power mode
kHzECO	32 kHz	Crystal dependent	32 kHz	Crystal dependent	500 ms typ, max is crystal dependent



Figure 6-1. Clocking Subsystem





# Notes

- The two VCCD pins must be connected together with as short a trace as possible. A trace under the device is recommended, as shown in Figure 2-8 on page 12.
- It is good practice to check the datasheets for your bypass capacitors, specifically the working voltage and the DC bias specifications. With some capacitors, the actual capacitance can decrease considerably when the DC bias (VDDX or VCCX in Figure 6-4) is a significant percentage of the rated working voltage.
- You can power the device in internally regulated mode, where the voltage applied to the VDDx pins is as high as 5.5 V, and the internal regulators provide the core voltages. In this mode, do not apply power to the VCCx pins, and do not tie the VDDx pins to the VCCx pins.
- You can also power the device in externally regulated mode, that is, by directly powering the VCCD and VCCA pins. In this configuration, the VDDD pins should be shorted to the VCCD pins and the VDDA pin should be shorted to the VCCA pin. The allowed supply range in this configuration is 1.71 V to 1.89 V. After power up in this configuration, the internal regulators are on by default, and should be disabled to reduce power consumption.



# 7.1.4 Designing with PSoC Creator

### 7.1.4.1 More Than a Typical IDE

A successful design tool allows for the rapid development and deployment of both simple and complex designs. It reduces or eliminates any learning curve. It makes the integration of a new design into the production stream straightforward.

PSoC Creator is that design tool.

PSoC Creator is a full featured Integrated Development Environment (IDE) for hardware and software design. It is optimized specifically for PSoC devices and combines a modern, powerful software development platform with a sophisticated graphical design tool. This unique combination of tools makes PSoC Creator the most flexible embedded design platform available.

Graphical design entry simplifies the task of configuring a particular part. You can select the required functionality from an extensive catalog of components and place it in your design. All components are parameterized and have an editor dialog that allows you to tailor functionality to your needs.

PSoC Creator automatically configures clocks and routes the I/O to the selected pins and then generates APIs to give the application complete control over the hardware. Changing the PSoC device configuration is as simple as adding a new component, setting its parameters, and rebuilding the project.

At any stage of development you are free to change the hardware configuration and even the target processor. To retarget your application (hardware and software) to new devices, even from 8- to 32-bit families, just select the new device and rebuild.

You also have the ability to change the C compiler and evaluate an alternative. Components are designed for portability and are validated against all devices, from all families, and against all supported tool chains. Switching compilers is as easy as editing the from the project options and rebuilding the application with no errors from the generated APIs or boot code.

# 7.1.4.2 Component Catalog

The component catalog is a repository of reusable design elements that select device functionality and customize your PSoC device. It is populated with an impressive selection of content; from simple primitives such as logic gates and device registers, through the digital timers, counters and PWMs, plus analog components such as ADC and DAC, and communication protocols, such as  $I^2C$ , and USB. See Example Peripherals on page 45 for more details about available peripherals. All content is fully characterized and carefully documented in datasheets with code examples, AC/DC specifications, and user code ready APIs.

# 7.1.4.3 Design Reuse

The symbol editor gives you the ability to develop reusable components that can significantly reduce future design time. Just draw a symbol and associate that symbol with your proven design. PSoC Creator allows for the placement of the new symbol anywhere in the component catalog along with the content provided by Cypress. You can then reuse your content as many times as you want, and in any number of projects, without ever having to revisit the details of the implementation.

#### 7.1.4.4 Software Development

Anchoring the tool is a modern, highly customizable user interface. It includes project management and integrated editors for C and assembler source code, as well the design entry tools.

Project build control leverages compiler technology from top commercial vendors such as ARM<sup>®</sup> Limited, Keil<sup>™</sup>, and CodeSourcery (GNU). Free versions of Keil C51 and GNU C Compiler (GCC) for ARM, with no restrictions on code size or end product distribution, are included with the tool distribution. Upgrading to more optimizing compilers is a snap with support for the professional Keil C51 product and ARM RealView<sup>™</sup> compiler.

# 7.1.4.5 Nonintrusive Debugging

With JTAG (4-wire) and SWD (2-wire) debug connectivity available on all devices, the PSoC Creator debugger offers full control over the target device with minimum intrusion. Breakpoints and code execution commands are all readily available from toolbar buttons and an impressive lineup of windows—register, locals, watch, call stack, memory and peripherals—make for an unparalleled level of visibility into the system.

PSoC Creator contains all the tools necessary to complete a design, and then to maintain and extend that design for years to come. All steps of the design flow are carefully integrated and optimized for ease-of-use and to maximize productivity.





# Figure 7-9. Digital System Interconnect

Interrupt and DMA routing is very flexible in the CY8C32 programmable architecture. In addition to the numerous fixed function peripherals that can generate interrupt requests, any data signal in the UDB array routing can also be used to generate a request. A single peripheral may generate multiple independent interrupt requests simplifying system and firmware design. Figure 7-10 shows the structure of the IDMUX (Interrupt/DMA Multiplexer).

# Figure 7-10. Interrupt and DMA Processing in the IDMUX

Interrupt and DMA Processing in IDMUX



# 7.4.1 I/O Port Routing

There are a total of 20 DSI routes to a typical 8-bit I/O port, 16 for data and four for drive strength control.

When an I/O pin is connected to the routing, there are two primary connections available, an input and an output. In

conjunction with drive strength control, this can implement a bidirectional I/O pin. A data output signal has the option to be single synchronized (pipelined) and a data input signal has the option to be double synchronized. The synchronization clock is the master clock (see Figure 6-1). Normally all inputs from pins are synchronized as this is required if the CPU interacts with the signal or any signal derived from it. Asynchronous inputs have rare uses. An example of this is a feed through of combinational PLD logic from input pins to output pins.

# Figure 7-11. I/O Pin Synchronization Routing



# Figure 7-12. I/O Pin Output Connectivity



There are four more DSI connections to a given I/O port to implement dynamic output enable control of pins. This connectivity gives a range of options, from fully ganged 8-bits controlled by one signal, to up to four individually controlled pins. The output enable signal is useful for creating tri-state bidirectional pins and buses.

# Figure 7-13. I/O Pin Output Enable Connectivity





# Table 11-2. DC Specifications (continued)

Parameter	Description	Conditions		Min	Typ <sup>[22]</sup>	Max	Units
	Sleep Mode <sup>[25]</sup>						
	CPU = OFF	V <sub>DD</sub> = V <sub>DDIO</sub> =	T = -40 °C	_	1.1	2.3	μA
	RTC = ON (= ECO32K ON, in low-power	4.5 V - 5.5 V	T = 25 °C	_	1.1	2.2	_
	Sleep timer = ON (= ILO ON at 1 kHz) <sup>[26]</sup>		T = 85 °C	-	15	30	
	WDT = OFF	V <sub>DD</sub> = V <sub>DDIO</sub> =	T = -40 °C	_	1	2.2	_
	Comparator = OFF	2.7 V – 3.6 V	T = 25 °C	-	1	2.1	
	POR = ON		T = 85 °C	-	12	28	
	Boost = OFF SIO pins in single ended input, unregulated output mode	V <sub>DD</sub> = V <sub>DDIO</sub> = 1.71 V – 1.95 V <sup>[27]</sup>	T = 25 °C	-	2.2	4.2	
	Comparator = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF $I^2C$ Wake = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode $I^2C$ Wake = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated	$V_{DD} = V_{DDIO} =$ 2.7 V - 3.6 V <sup>[28]</sup> $V_{DD} = V_{DDIO} =$ 2.7 V - 3.6 V <sup>[28]</sup>	T = 25 °C T = 25 °C	-	2.2	2.7	
	Hibernate Mode <sup>[25]</sup>						
	Hibernate mode current	V <sub>DD</sub> = V <sub>DDIO</sub> =	T =40 °C	_	0.2	1.5	μA
	All regulators and oscillators off	4.5 V - 5.5 V	T = 25 °C	_	0.5	1.5	1
	GPIO interrupts are active		T = 85 °C	_	4.1	5.3	
	Boost = OFF	V <sub>DD</sub> = V <sub>DDIO</sub> =	T =40 °C	_	0.2	1.5	
	SIO pins in single ended input, unregulated	2.7 V – 3.6 V	T = 25 °C	_	0.2	1.5	
	mode		T = 85 °C	_	3.2	4.2	
		$V_{DD} = V_{DDIO} = \dots$	T = -40 °C	_	0.2	1.5	
		1.71 V – 1.95 V <sup>[27]</sup>	T = 25 °C	_	0.3	1.5	
			T = 85 °C	_	3.3	4.3	
I <sub>DDAR</sub>	Analog current consumption while device is	$V_{DDA} \le 3.6 \text{ V}$	<u>.</u>	_	0.3	0.6	mA
	reset <sup>i29]</sup>	V <sub>DDA</sub> > 3.6 V		-	1.4	3.3	mA
I <sub>DDDR</sub>	Digital current consumption while device is	$V_{DDD} \le 3.6 \text{ V}$		-	1.1	3.1	mA
	reset <sup>i29]</sup>	$V_{DDD} > 3.6 V$		_	0.7	3.1	mA



# Table 11-3. AC Specifications<sup>[30]</sup>

Parameter	Description	Conditions	Min	Тур	Max	Units
F <sub>CPU</sub>	CPU frequency	$1.71~V \le V_{DDD} \le 5.5~V$	DC	-	50.01	MHz
F <sub>BUSCLK</sub>	Bus frequency	$1.71~V \le V_{DDD} \le 5.5~V$	DC	_	50.01	MHz
Svdd	V <sub>DD</sub> ramp rate		-	-	0.066	V/µs
T <sub>IO_INIT</sub>	Time from $V_{DDD}/V_{DDA}/V_{CCD}/V_{CCA} \ge$ IPOR to I/O ports set to their reset states		-	-	10	μs
T <sub>STARTUP</sub>	Time from $V_{DDD}/V_{DDA}/V_{CCD}/V_{CCA} \ge PRES$ to CPU executing code at reset vector	$V_{CCA}/V_{CCD}$ = regulated from $V_{DDA}/V_{DDD}$ , no PLL used, IMO boot mode (12 MHz typ.)	-	-	74	μs
T <sub>SLEEP</sub>	Wakeup from sleep mode – Application of non-LVD interrupt to beginning of execution of next CPU instruction		-	-	15	μs
T <sub>HIBERNATE</sub>	Wakeup from hibernate mode – Application of external interrupt to beginning of execution of next CPU instruction		-	_	100	μs

Figure 11-4. F<sub>CPU</sub> vs. V<sub>DD</sub>



Note 30. Based on device characterization (Not production tested).



# 11.3 Power Regulators

Specifications are valid for –40 °C  $\leq$  T<sub>A</sub>  $\leq$  85 °C and T<sub>J</sub>  $\leq$  100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

# 11.3.1 Digital Core Regulator

# Table 11-4. Digital Core Regulator DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
V <sub>DDD</sub>	Input voltage		1.8	-	5.5	V
V <sub>CCD</sub>	Output voltage		-	1.80	-	V
	Regulator output capacitor	$\pm$ 10%, X5R ceramic or better. The two V <sub>CCD</sub> pins must be shorted together, with as short a trace as possible, see Power System on page 31	0.9	1	1.1	μF

# Figure 11-5. Regulators V<sub>CC</sub> vs V<sub>DD</sub>



# Figure 11-6. Digital Regulator PSRR vs Frequency and V<sub>DD</sub>



# 11.3.2 Analog Core Regulator

# Table 11-5. Analog Core Regulator DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
V <sub>DDA</sub>	Input voltage		1.8	-	5.5	V
V <sub>CCA</sub>	Output voltage		-	1.80	-	V
	Regulator output capacitor	±10%, X5R ceramic or better	0.9	1	1.1	μF

Figure 11-7. Analog Regulator PSRR vs Frequency and  $V_{DD}$ 





# 11.3.3 Inductive Boost Regulator

Unless otherwise specified, operating conditions are:  $V_{BAT} = 0.5 V-3.6 V$ ,  $V_{OUT} = 1.8 V-5.0 V$ ,  $I_{OUT} = 0 mA-50 mA$ ,  $L_{BOOST} = 4.7 \mu H-22 \mu H$ ,  $C_{BOOST} = 22 \mu F \parallel 3 \times 1.0 \mu F \parallel 3 \times 0.1 \mu F$ ,  $C_{BAT} = 22 \mu F$ ,  $I_F = 1.0 A$ . Unless otherwise specified, all charts and graphs show typical values.

Table 11-6	Inductive	Boost	Regulator	DC S	pecifications
		20031	regulator	000	peemeanons

Parameter	Description	Cond	ditions	Min	Тур	Max	Units
V <sub>OUT</sub>	Boost output voltage <sup>[31]</sup>	vsel = 1.8 V in regist	er BOOST_CR0	1.71	1.8	1.89	V
		vsel = 1.9 V in regist	vsel = 1.9 V in register BOOST_CR0		1.90	2.00	V
		vsel = 2.0 V in regist	1.90	2.00	2.10	V	
		vsel = 2.4 V in regist	er BOOST_CR0	2.16	2.40	2.64	V
		vsel = 2.7 V in regist	er BOOST_CR0	2.43	2.70	2.97	V
		vsel = 3.0 V in regist	er BOOST_CR0	2.70	3.00	3.30	V
		vsel = 3.3 V in regist	er BOOST_CR0	2.97	3.30	3.63	V
		vsel = 3.6 V in regist	er BOOST_CR0	3.24	3.60	3.96	V
		vsel = 5.0 V in regist	er BOOST_CR0	4.50	5.00	5.50	V
V <sub>BAT</sub>	Input voltage to boost <sup>[32]</sup>	I <sub>OUT</sub> = 0 mA–5 mA	vsel = 1.8 V–2.0 V, T <sub>A</sub> = 0 °C–70 °C	0.5	-	0.8	V
		I <sub>OUT</sub> = 0 mA–15 mA	vsel = 1.8 V–5.0 V <sup>[33]</sup> , T <sub>A</sub> = –10 °C–85 °C	1.6	-	3.6	V
		I <sub>OUT</sub> = 0 mA–25 mA	vsel = 1.8 V–2.7 V, T <sub>A</sub> = –10 °C–85 °C	0.8	-	1.6	V
		I <sub>OUT</sub> = 0 mA–50 mA	vsel = 1.8 V–3.3 V <sup>[33]</sup> , T <sub>A</sub> = –40 °C–85 °C	1.8	-	2.5	V
			vsel = 1.8 V–3.3 V <sup>[33]</sup> , T <sub>A</sub> = –10 °C–85 °C	1.3	-	2.5	V
			vsel = 2.5 V–5.0 V <sup>[33]</sup> , T <sub>A</sub> = –10 °C–85 °C	2.5	-	3.6	V
I <sub>OUT</sub>	Output current	T <sub>A</sub> = 0 °C–70 °C	V <sub>BAT</sub> = 0.5 V–0.8 V	0	-	5	mA
		T <sub>A</sub> = −10 °C−85 °C	V <sub>BAT</sub> = 1.6 V–3.6 V	0	_	15	mA
			V <sub>BAT</sub> = 0.8 V–1.6 V	0	_	25	mA
			V <sub>BAT</sub> = 1.3 V–2.5 V	0	_	50	mA
			V <sub>BAT</sub> = 2.5 V–3.6 V	0	-	50	mA
		T <sub>A</sub> = -40 °C-85 °C	V <sub>BAT</sub> = 1.8 V–2.5 V	0	-	50	mA
I <sub>LPK</sub>	Inductor peak current			-	_	700	mA
IQ	Quiescent current	Boost active mode		-	250	-	μA
		Boost sleep mode, I	<sub>OUT</sub> < 1 μA	_	25	_	μA
Reg <sub>LOAD</sub>	Load regulation			_	-	10	%
Reg <sub>LINE</sub>	Line regulation			-	-	10	%

#### Notes

- 31. Listed vsel options are characterized. Additional vsel options are valid and guaranteed by design.
   32. The boost will start at all valid V<sub>BAT</sub> conditions including down to V<sub>BAT</sub> = 0.5 V.
   33. If V<sub>BAT</sub> is greater than or equal to V<sub>OUT</sub> boost setting, then V<sub>OUT</sub> will be less than V<sub>BAT</sub> due to resistive losses in the boost circuit.





# Figure 11-11. Efficiency vs V<sub>BAT</sub>, $L_{BOOST}$ = 4.7 $\mu$ H <sup>[35]</sup>

Figure 11-13. Efficiency vs V<sub>BAT</sub>, L<sub>BOOST</sub> = 22  $\mu$ H <sup>[35]</sup>



Figure 11-12. Efficiency vs  $V_{BAT}$ ,  $L_{BOOST}$  = 10  $\mu$ H <sup>[35]</sup>



Figure 11-14. V<sub>RIPPLE</sub> vs V<sub>BAT</sub> <sup>[35]</sup>



#### Note

35. Typical example. Actual values may vary depending on external component selection, PCB layout, and other design parameters.



# Table 11-13. SIO Comparator Specifications<sup>[42]</sup>

Parameter	Description	Conditions	Min	Тур	Max	Units
Vos	Offset voltage	V <sub>DDIO</sub> = 2 V	-	_	68	mV
		V <sub>DDIO</sub> = 2.7 V	-	_	72	
		V <sub>DDIO</sub> = 5.5 V	-	_	82	
TCVos	Offset voltage drift with temp		-	-	250	µV/°C
CMRR	Common mode rejection ratio	V <sub>DDIO</sub> = 2 V	30	-	_	dB
		V <sub>DDIO</sub> = 2.7 V	35	_	-	
		V <sub>DDIO</sub> = 5.5 V	40	-	-	
Tresp	Response time		-	-	30	ns

# 11.4.3 USBIO

For operation in GPIO mode, the standard range for  $V_{DDD}$  applies, see Device Level Specifications on page 68.

# Table 11-14. USBIO DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
Rusbi	USB D+ pull-up resistance	With idle bus	0.900	_	1.575	kΩ
Rusba	USB D+ pull-up resistance	While receiving traffic	1.425	-	3.090	kΩ
Vohusb	Static output high	15 k $\Omega$ ±5% to Vss, internal pull-up enabled	2.8	_	3.6	V
Volusb	Static output low	15 k $\Omega$ ±5% to Vss, internal pull-up enabled	-	_	0.3	V
Vohgpio	Output voltage high, GPIO mode	$I_{OH}$ = 4 mA, $V_{DDD} \ge 3 V$	2.4	_	_	V
Volgpio	Output voltage low, GPIO mode	$I_{OL}$ = 4 mA, $V_{DDD} \ge 3 V$	_	_	0.3	V
Vdi	Differential input sensitivity	(D+)–(D–)	-	-	0.2	V
Vcm	Differential input common mode range	-	0.8	_	2.5	V
Vse	Single ended receiver threshold	-	0.8	_	2	V
Rps2	PS/2 pull-up resistance	In PS/2 mode, with PS/2 pull-up enabled	3	_	7	kΩ
Rext	External USB series resistor	In series with each USB pin	21.78 (–1%)	22	22.22 (+1%)	Ω
Zo	USB driver output impedance	Including Rext	28	_	44	Ω
C <sub>IN</sub>	USB transceiver input capacitance	-	_	-	20	pF
I <sub>IL</sub> <sup>[42]</sup>	Input leakage current (absolute value)	25 °C, V <sub>DDD</sub> = 3.0 V	-	-	2	nA



# Table 11-29. VDAC AC Specifications t

Parameter	Description	Conditions	Min	Тур	Max	Units
F <sub>DAC</sub>	Update rate	1 V scale	-	-	1000	ksps
		4 V scale	-	-	250	ksps
TsettleP	Settling time to 0.1%, step 25% to 75%	1 V scale, Cload = 15 pF	-	0.45	1	μs
		4 V scale, Cload = 15 pF	-	0.8	3.2	μs
TsettleN	Settling time to 0.1%, step 75% to 25%	1 V scale, Cload = 15 pF	_	0.45	1	μs
		4 V scale, Cload = 15 pF	-	0.7	3	μs
	Voltage noise	Range = 1 V, High speed mode, V <sub>DDA</sub> = 5 V, 10 kHz	1	750	-	nV/sqrtHz

# Figure 11-48. VDAC Step Response, Codes 0x40 - 0xC0, 1 V Mode, High speed mode, $V_{DDA} = 5 V$







Figure 11-49. VDAC Glitch Response, Codes 0x7F - 0x80, 1 V Mode, High speed mode,  $V_{\text{DDA}}$  = 5 V













Table 11-55. Synchronous Read Cycle Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
Т	EMIF clock period <sup>[62]</sup>	$V_{DDA} \ge 3.3 V$	30.3	_	-	ns
Tcp/2	EM_Clock pulse high		T/2	-	-	ns
Tceld	EM_CEn low to EM_Clock high		5	-	-	ns
Tcehd	EM_Clock high to EM_CEn high		T/2 – 5	-	-	ns
Taddrv	EM_Addr valid to EM_Clock high		5	-	-	ns
Taddriv	EM_Clock high to EM_Addr invalid		T/2 – 5	-	-	ns
Toeld	EM_OEn low to EM_Clock high		5	-	-	ns
Toehd	EM_Clock high to EM_OEn high		Т	-	-	ns
Tds	Data valid before EM_OEn high		T + 15	-	-	ns
Tadscld	EM_ADSCn low to EM_Clock high		5	-	-	ns
Tadschd	EM_Clock high to EM_ADSCn high		T/2 – 5	_	-	ns



# 11.8.3 Interrupt Controller

# Table 11-61. Interrupt Controller AC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
	Delay from interrupt signal input to ISR code execution from ISR code	Includes worse case completion of longest instruction DIV with 6 cycles	-	-	25	Tcy CPU

# 11.8.4 JTAG Interface





|--|

Parameter	Description	Conditions	Min	Тур	Max	Units
f_TCK	TCK frequency	$3.3 \text{ V} \leq \text{V}_{DDD} \leq 5 \text{ V}$	-	-	14 <sup>[66]</sup>	MHz
		$1.71 \text{ V} \le \text{V}_{\text{DDD}} < 3.3 \text{ V}$	-	_	7 <sup>[66]</sup>	MHz
T_TDI_setup	TDI setup before TCK high		(T/10)-5	-	-	ns
T_TMS_setup	TMS setup before TCK high		T/4	-	-	
T_TDI_hold	TDI, TMS hold after TCK high	T = 1/f_TCK max	T/4	_	-	
T_TDO_valid	TCK low to TDO valid	T = 1/f_TCK max	-	-	2T/5	
T_TDO_hold	TDO hold after TCK high	T = 1/f_TCK max	T/4	_	—	

Notes

65. Based on device characterization (Not production tested).
 66. f\_TCK must also be no more than 1/3 CPU clock frequency.



# Figure 11-59. IMO Current vs. Frequency



# Table 11-66. IMO AC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units				
	IMO frequency stability (with factory trim)									
	24 MHz – Non USB mode		-4	-	4	%				
E	24 MHz – USB mode	With oscillator locking to USB bus	-0.25	_	0.25	%				
LINO	12 MHz		-3	_	3	%				
	6 MHz		-2	-	2	%				
	3 MHz		-2	-	2	%				
	Startup time <sup>[69]</sup>	From enable (during normal system operation)	_	-	13	μs				
	Jitter (peak to peak) <sup>[69]</sup>	·								
Jp-p	F = 24 MHz		_	0.9	_	ns				
	F = 3 MHz		_	1.6	_	ns				
Jperiod	Jitter (long term) <sup>[69]</sup>									
	F = 24 MHz		-	0.9	-	ns				
	F = 3 MHz		_	12	-	ns				

# Figure 11-60. IMO Frequency Variation vs. Temperature



# Figure 11-61. IMO Frequency Variation vs. V<sub>CC</sub>



# Note

69. Based on device characterization (Not production tested).



# 17. Revision History

Descript Docume	Description Title: PSoC <sup>®</sup> 3: CY8C32 Family Data Sheet Programmable System-on-Chip (PSoC <sup>®</sup> ) Document Number: 001-56955							
Revision	ECN	Submission Date	Orig. of Change	Description of Change				
**	2796903	11/04/09	MKEA	New datasheet				
*A	2824546	12/09/09	MKEA	Updated I2C section to reflect 1 Mbps. Updated Table 11-6 and 11-7 (Boost AC and DC specs); also added Shottky Diode specs. Changed current for sleep/hibernate mode to include SIO; Added footnote to analog global specs. Updated Figures 1-1, 6-2, 7-14, and 8-1. Updated Table 6-2 and Table 6-3 (Hibernate and Sleep rows) and Power Modes section. Updated GPIO and SIO AC specifications. Updated Gain error in IDAC and VDAC specifications. Updated description of V <sub>DDA</sub> spec in Table 11-1 and removed GPIO Clamp Current parameter. Updated number of UDBs on page 1. Moved FILO from ILO DC to AC table. Added PCB Layout and PCB Schematic diagrams. Updated Fgpioout spec (Table 11-9). Added duty cycle frequency in PLL AC spec table. Added note for Sleep and Hibernate modes and Active Mode specs in Table 11-2. Linked URL in Section 10.3 to PSoC Creator site. Updated Ja and Jc values in Table 13-1. Updated Single Sample Mode and Fast FIR Mode sections. Updated Input Resistance specification in Del-Sig ADC table. Added Tio_init parameter. Updated PGA and UGB AC Specs. Removed SPC ADC. Updated Boost Converter section. Added section 'SIO as Comparator'; updated Hysteresis spec (differential mode) in Table 11-10. Updated V <sub>BAT</sub> condition and deleted Vstart parameter in Table 11-6. Added 'Bytes' column for Tables 4-1 to 4-5.				
*В	2873322	02/04/10	MKEA	Changed maximum value of PPOR_TR to '1'. Updated V <sub>BIAS</sub> specification. Updated PCB Schematic. Updated Figure 8-1 and Figure 6-3. Updated Interrupt Vector table, Updated Sales links. Updated JTAG and SWD specifications. Removed Jp-p and Jperiod from ECO AC Spec table. Added note on sleep timer in Table 11-2. Updated ILO AC and DC specifications. Added Resolution parameter in VDAC and IDAC tables. Updated I <sub>OUT</sub> typical and maximum values. Changed Temperature Sensor range to -40 °C to +85 °C. Removed Latchup specification from Table 11-1. Updated DAC details				



Descript Docume	Description Title: PSoC <sup>®</sup> 3: CY8C32 Family Data Sheet Programmable System-on-Chip (PSoC <sup>®</sup> ) (continued) Document Number: 001-56955							
Revision	ECN	Submission Date	Orig. of Change	Description of Change				
*D	2938381	05/27/10	MKEA	Replaced V <sub>DDIO</sub> with V <sub>DDD</sub> in USBIO diagram and specification tables, added text in USBIO section of Electrical Specifications. Added Table 13-2 (Package MSL) Modified Tstorag condition and changed max spec to 100 Added bullet (Pass) under ALU (section 7.2.2.2) Added figures for kHzECO and MHzECO in the External Oscillator section Updated Figure 6-1(Clocking Subsystem diagram) Removed CPUCLK_DIV in table 5-2, Deleted Clock Divider SFR subsection Updated PSoC Creator Framework image Updated SIO DC Specifications (V <sub>IH</sub> and V <sub>IL</sub> parameters) Updated bullets in Clocking System and Clocking Distribution sections Updated Figure 8-2 Updated Table 11-10 Updated PCB Layout and Schematic, updated as per MTRB review comments Updated Table 6-3 (power changed to current) In 32kHZ EC DC Specifications table, changed I <sub>CC</sub> Max to 0.25 In IMO DC Specifications table, updated Supply Current values Updated GPIO DC Specs table Modified to support a maximum 50MHz CPU speed				
*E	2958674	06/22/10	SHEA	Minor ECN to post datasheet to external website				
*F	2989685	08/04/10	MKEA	Added USBIO 22 ohm DP and DM resistors to Simplified Block Diagram Added to Table 6-6 a footnote and references to same. Added sentences to the resistive pull-up and pull-down description bullets. Added sentence to Section 6.4.11, Adjustable Output Level. Updated section 5.5 External Memory Interface Updated Table 11-73 JTAG Interface AC Specifications Updated Table 11-74 SWD Interface AC Specifications				
*G	3078568	11/04/10	MKEA	Updated "Current Digital-to-analog Converter (IDAC)" on page 87 Updated "Voltage Digital to Analog Converter (VDAC)" on page 92 Updated Table 11-2, "DC Specifications," on page 68				
*Н	3107314	12/10/2010	MKEA	Updated delta-sigma tables and graphs. Updated Flash AC specs Formatted table 11.2. Updated interrupt controller table Updated transimpedance amplifier section Updated SIO DC specs table Updated Voltage Monitors DC Specifications table Updated LCD Direct Drive DC specs table Updated ESD <sub>HBM</sub> value. Updated IDAC and VDAC sections Removed ESO parts from ordering information Changed USBIO pins from NC to DNU and removed redundant USBIO pin description notes Updated POR with brown out DC and AC specs Updated 32 kHz External Crystal DC Specifications Updated Inductive boost regulator section Delta sigma ADC spec updates Updated comparator section Removed buzz mode from Power Mode Transition diagram				
*	3179219	02/22/2011	MKEA	Updated conditions for flash data retention time. Updated 100-pin TQFP package spec. Updated EEPROM AC specifications.				